

<b>Notice of References Cited</b>	Application/Control No. 10/758,435	Applicant(s)/Patent Under Reexamination JAMNEALA ET AL.	
	Examiner Elias Desta	Art Unit 2857	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-4,808,913	02-1989	Grace, Martin I.	324/638
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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	U	Ferrero et al., 'Comparison Between a Vector Multi-Port Network Analyzer and the National S-Parameter Measurement System', January 1995, IEEE Article, pages 143-144
	V	Bockelman et al., 'Calibration and Verification of the Pure-Mode Vector Network Analyzer', 1998, IEEE Article, Vol. 46, No. 7, pages 1009-1012
	W	Wiatr et al., 'Simultaneous Noise and Vector Network Analysis Using Radiometer Systems', January 1999, IEEE Article, pages 198-229
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.